IN THE CLAIMS:

1. (Withdrawn) A stripping composition for removing a photoresist including novolak, the stripping composition comprising:

an acetic acid; and an ozone gas included in the acetic acid as a bubble form.

- 2. (Withdrawn) The stripping composition of claim 1, wherein a pH of the stripping composition is about 1.6 to about 5.0.
- 3. (Withdrawn) The stripping composition of claim 1, wherein a concentration of the ozone gas included in the acetic acid is about 80,000 to about 90,000ppm.
- 4. (Currently amended) A method of forming a pattern, the method comprising: forming a photoresist pattern including novolak on a layer formed on a substrate; etching the layer using the photoresist pattern using as a mask to form a pattern on the substrate; and

removing the photoresist pattern using a stripping composition including an acetic acid and an ozone gas included in the acetic acid in the form of a bubble, wherein a pH of the stripping composition is about 1.6 to about 5, and

wherein a concentration of the ozone gas included in the acetic acid is about 80,000 to about 90,000 ppm.

- 5. (Original) The method of claim 4, wherein the stripping composition is prepared by bubbling the ozone gas in the acetic acid.
 - 6. (Canceled)
- 7. (Original) The method of claim 4, wherein the removing the photoresist pattern further comprises:

spraying the stripping composition onto the photoresist pattern to wet the photoresist pattern; and

rinsing the photoresist pattern.

- 8. (Original) The method of claim 7, wherein the photoresist pattern is rinsed using water.
- 9. (Original) The method of claim 7, wherein the spraying the stripping composition further comprises:

moving the substrate in a first direction during spraying the stripping composition onto the photoresist pattern; and

moving the substrate in a second direction opposed to the first direction during spraying the stripping composition onto the photoresist pattern.

- 10. (Canceled).
- 11. (Original) The method of claim 4, wherein the layer comprises a gate layer having a first gate wiring layer and a second gate wiring layer,

and wherein, the method further comprises:

etching the second gate wiring layer using the photoresist pattern as a mask to form a second gate wiring layer pattern;

removing the photoresist pattern using the stripping composition; and etching the first gate wiring layer to form a first gate wiring layer pattern.

- 12. (Original) The method of claim 11, wherein the gate layer comprises a Cr layer and an Al layer.
- 13. (Original) The method of claim 11, wherein the photoresist pattern is removed using the stripping composition after etching the first and second gate wiring layers using an etching gas.
 - 14. (Original) The method of claim 13, wherein the etching gas comprises a chlorine gas.

15. (Previously presented) The method of claim 11, wherein the photoresist pattern is removed by using the stripping composition after a contact hole is formed according to etching the first and second gate wiring layers.

16. (Original) A method of manufacturing a TFT substrate for an LCD device, the method comprising:

forming a first gate wiring layer and a second gate wiring layer on a substrate;

forming a first photoresist pattern including novolak;

etching the second gate wiring layer using the first photoresist pattern as an etching mask;

removing the first photoresist pattern using a stripping composition including an acetic acid and an ozone gas included in the acetic acid as a bubble form;

etching the first gate wiring layer to form a gate pattern having a gate

etching the first gate wiring layer to form a gate pattern having a gate line, a gate pad and a gate electrode;

forming a gate insulation layer on the substrate having the gate pattern;

forming a semiconductor layer and a doped amorphous silicon layer on the gate insulation layer;

forming a semiconductor layer pattern and an ohmic contact pattern by etching the semiconductor layer and the doped amorphous silicon layer;

forming a conductive material on the semiconductor layer pattern and on the ohmic contact pattern;

forming a data line, a source electrode and a drain electrode by etching the conductive material;

forming a passivation layer on the data line, the source electrode and the drain electrode; forming a second photoresist pattern including novolak on the passivation layer; etching the passivation layer to form a contact hole partially exposing the drain electrode; removing the second photoresist pattern using a stripping composition including an acetic acid and an ozone gas included in the acetic acid as a bubble form; and

forming and etching transparent conductive material layer to form a pixel electrode.

17. (Original) A method of manufacturing a TFT substrate for an LCD apparatus, the method comprising:

forming a gate pattern having a gate line, a gate pad and a gate electrode on a substrate; forming a gate insulation layer on the substrate having the gate pattern;

forming a semiconductor layer, an intermediate layer and a conductive layer on the gate insulation layer;

forming a photoresist film including novolak on the conductive layer;

exposing and developing the photoresist film to form a photoresist pattern having a first region formed in a channel region disposed between a source electrode and a drain electrode successively formed and a second region formed in a data wiring region successively formed, the first region having a thickness thinner than a thickness of the second region;

etching the conductive layer, the intermediate layer and the semiconductor layer using the photoresist pattern as an etching mask to form a semiconductor layer pattern in the channel region, and to form the semiconductor layer pattern, an intermediate layer pattern and a conductive layer pattern in the data wiring region so that a data line, the source electrode and the drain electrode are formed in the channel and the data wiring regions;

removing the photoresist pattern using a stripping composition including an acetic acid and an ozone gas included in the acetic acid as a bubble form;

forming a passivation layer on the data line, the source electrode and the drain electrode; etching the passivation layer to form a contact hole partially exposing the drain electrode;

forming and etching transparent conductive material layer to form, a pixel electrode.

IY-200209-001-1-US0 LW8080PC-US/CH 21C-0329

and

18. (Original) A method of manufacturing a TFT substrate for an LCD apparatus, the method comprising:

forming a data wiring having a data line on a insulation substrate;

forming a red color filter, a green color filter and a blue color filter on the substrate;

forming a buffer layer covering the data wiring and the color filters;

forming a gate wiring layer on the buffer layer;

forming a photoresist pattern including novolak on the gate wiring layer;

etching the gate wiring layer using the photoresist pattern as an etching mask to form a gate wiring having a gate line and a gate electrode;

removing the photoresist pattern using a stripping composition including an acetic acid and an ozone gas included in the acetic acid as a bubble form;

forming a gate insulation layer to cover the gate wiring;

forming an ohmic contact layer pattern of an island shape and a semiconductor layer pattern on the gate insulation layer, and simultaneously forming a first contact hole through the gate insulation layer and the buffer layer to partially expose the data line;

forming a pixel wiring including a source and a drain electrodes separately formed on the ohmic contact layer pattern, and a pixel electrode connected to the drain electrode, the source and the drain electrodes substantially including identical material; and

removing an exposed portion of the ohmic contact layer pattern between the source electrode and the drain electrode to separate-the ohmic contact-layer pattern.